Chip Monolithic Ceramic Capacitors (Medium Voltage)

For Information Devices GR4 Series

■ Features

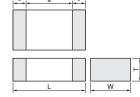
- These items are designed specifically for telecommunications devices (IEEE802.3) in Ethernet LAN and primary-secondary coupling for DC-DC converters.
- 2. A new monolithic structure for small, high capacitance capable of operating at high voltage levels
- 3. Sn-plated external electrodes realize good solderability.
- 4. Only for reflow soldering

Applications

- Ideal for use on telecommunications devices in Ethernet LAN
- 2. Ideal for use as primary-secondary coupling for DC-DC converters

Do not use these products in any Automotive Power train or Safety equipment including Battery charger for Electric Vehicles and Plug-in Hybrid. Only Murata products clearly stipulated as "for Automotive use" can be used for automobile applications such as Power train and Safety equipment.





Doub Number	Dimensions (mm)						
Part Number	L	W	T	e min.	g min.		
GR442Q	4.5 ±0.3	2.0 ±0.2	1.5 +0, -0.3				
GR443D	45.04	00.00	2.0 +0, -0.3	0.3	2.5		
GR443Q	4.5 ±0.4	3.2 ±0.3	1.5 +0, -0.3	0.3			
GR455D	5.7 ±0.4	5.0 ±0.4	2.0 +0, -0.3		3.2		

Part Number	Rated Voltage	TC Code (Standard)	Capacitance	Length L (mm)	Width W (mm)	Thickness T max. (mm)	Electrode g min.	Electrode e
GR442QR73D101KW01L	2000Vdc	X7R (EIA)	100pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D121KW01L	2000Vdc	X7R (EIA)	120pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D151KW01L	2000Vdc	X7R (EIA)	150pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D181KW01L	2000Vdc	X7R (EIA)	180pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D221KW01L	2000Vdc	X7R (EIA)	220pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D271KW01L	2000Vdc	X7R (EIA)	270pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D331KW01L	2000Vdc	X7R (EIA)	330pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D391KW01L	2000Vdc	X7R (EIA)	390pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D471KW01L	2000Vdc	X7R (EIA)	470pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D561KW01L	2000Vdc	X7R (EIA)	560pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D681KW01L	2000Vdc	X7R (EIA)	680pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D821KW01L	2000Vdc	X7R (EIA)	820pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D102KW01L	2000Vdc	X7R (EIA)	1000pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D122KW01L	2000Vdc	X7R (EIA)	1200pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR442QR73D152KW01L	2000Vdc	X7R (EIA)	1500pF±10%	4.5	2	1.5	2.5mm	0.3mm min.
GR443QR73D182KW01L	2000Vdc	X7R (EIA)	1800pF±10%	4.5	3.2	1.5	2.5mm	0.3mm min.
GR443QR73D222KW01L	2000Vdc	X7R (EIA)	2200pF±10%	4.5	3.2	1.5	2.5mm	0.3mm min.
GR443QR73D272KW01L	2000Vdc	X7R (EIA)	2700pF±10%	4.5	3.2	1.5	2.5mm	0.3mm min.
GR443QR73D332KW01L	2000Vdc	X7R (EIA)	3300pF±10%	4.5	3.2	1.5	2.5mm	0.3mm min.
GR443QR73D392KW01L	2000Vdc	X7R (EIA)	3900pF±10%	4.5	3.2	1.5	2.5mm	0.3mm min.
GR443DR73D472KW01L	2000Vdc	X7R (EIA)	4700pF±10%	4.5	3.2	2	2.5mm	0.3mm min.
GR455DR73D103KW01L	2000Vdc	X7R (EIA)	10000pF±10%	5.7	5	2	3.2mm	0.3mm min.



GR4 Series Specifications and Test Methods

No.	Ite	em	Specifications	Test Method				
1	Operating Temperatu	ire Range	−55 to +125°C		-			
2	Appearan	ice	No defects or abnormalities	Visual inspection				
3	Dimensio	ns	Within the specified dimensions	Using calipers and micrometers				
4	Dialo atrio	Odmon adda	No defeate ou abacumatities	No failure should be observed when voltage in the table is applied between the terminations, provided the charge/discharge current is less than 50mA.				
4	Dielectric	Strength	No defects or abnormalities	Rated Voltage	Test Voltage	Time		
				DC2kV	120% of the rated voltage AC1500V(r.m.s.)	60±1 sec. 60±1 sec.		
5	Pulse Vol	tage	No self healing breakdowns or flash-overs have taken place in the capacitor.	10 impulses of alternating polarity are subjected. (5 impulses for each polarity) The interval between impulses is 60 sec. Applied Pulse: 1.2/50µs Applied Voltage: 2.5kVo-p				
6	Insulation F (I.R.)	Resistance	More than $6{,}000M\Omega$	The insulation resist and within 60±5 sec	tance should be measured w c. of charging.	ith DC500±50V		
7	Capacitar	nce	Within the specified tolerance	The capacitance/D	E should be measured at a	froguency of		
8	Dissipation Factor (D.		0.025 max.	The capacitance/D.F. should be measured at a frequency of 1±0.2kHz and a voltage of AC1±0.2V(r.m.s.).				
9	Capacitance 9 Temperature Characteristics		Cap. Change within ±15% (Temp. Range: –55 to +125°C)	The capacitance measurement should be made at each step specified in the Table. Step				
10	Adhesive Strength of Termination		No removal of the terminations or other defect should occur.	Solder the capacitor to the testing jig (glass epoxy board in Fig. 1. Then apply 10N force in the direction of the arrow. The soldering should be done using the reflow method a should be conducted with care so that the soldering is used and free of defects such as heat shock.				
		Appearance	No defects or abnormalities	Solder the capacito	r to the test jig (glass epoxy l	ooard).		
		Capacitance	Within the specified tolerance		ld be subjected to a simple h tude of 1.5mm, the frequenc			
11	Vibration Resistance	/ibration		uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 min. This motion should be applied for a period of 2 hrs. in each of 3 mutually perpendicular directions (total of 6 hrs.). Solder resist Glass Epoxy Board				

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

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GR4 Series Specifications and Test Methods

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No.	Ite	em	Specifications					Test Method				
12	Deflection	n	L×W (mm) 4.5×2.0 4.5×3.2 5.7×5.0	a 3.5 3.5 4.5	100 Fig. 2 Dimens b 7.0 7.0 8.0	64.5 t:1.6	d 1.0	Solder the capacitor to the testing jig (glass epoxy board) shown in Fig. 2. Then apply a force in the direction shown in Fig. 3. The soldering should be done using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Pressurizing speed: 1.0mm/s Pressurize Pressurize Flexure=1 Capacitance meter Fig. 3				
13	Solderability of Termination 75% of the terminations are to be soldered evenly and continuously.				d continuously.	Immerse the capacitor in a solution of ethanol (JIS-K-8101) and rosin (JIS-K-5902) (25% rosin in weight proportion). Immerse in solder solution for 2±0.5 sec. Immersing speed: 25±2.5mm/s Temp. of solder: 245±5°C Lead Free Solder (Sn-3.0Ag-0.5Cu) 235±5°C H60A or H63A Eutectic Solder						
		Appearance	No marking def	ects				Preheat the capacitor as in table.				
		Capacitance Change	Within ±10%					Immerse the capacitor in solder solution at 260±5°C for 10±1 sec. Let sit at room condition* for 24±2 hrs., then measure. •Immersing speed: 25±2.5mm/s				
	Resistance	D.F.	0.025 max.					•Pretreatment				
14	to Soldering	I.R.	More than 1,00	0ΜΩ				Perform a heat treatment at 150 [±] ₁ %°C for 60±5 min. and let sit for 24±2 hrs. at room condition.*				
	Heat	Dielectric Strength	In accordance	with item N	0.4			*Preheating Step 1 2	Temperature 100 to 120°C 170 to 200°C	Time 1 min. 1 min.		
		Appearance	No marking def	ects				Fix the capacitor to the supporting jig (glass epoxy board) shown in Fig. 4. Perform the 5 cycles according to the 4 heat treatments listed in the following table. Let sit for 24±2 hrs. at room condition,* then measure.				
		Capacitance Change	Within ±15%									
		D.F.	0.05 max.									
		I.R.	More than 3,00	0ΜΩ				Step	Temperature (°C)	Time (min.)		
15	Temperature							1 2 3 4	Min. Operating Temp.±3 Room Temp. Max. Operating Temp.±2 Room Temp.	30±3 2 to 3 30±3 2 to 3		
13	Cycle	Dielectric Strength	In accordance v	with item N	0.4				eat treatment at 150±18°C for the second treatme	er resist		
		Appearance	No marking defects									
	Humidity	Capacitance Change	Within ±15%					Let the capacitor sit at 40±2°C and relative humidity of 90 to 95% for 500±26 hrs. Remove and let sit for 24±2 hrs. at room condition,* then				
16	(Steady	D.F.	0.05 max.					measure.		SG. 11011		
	State)	I.R.	More than 1,00	0ΜΩ				•Pretreatment Perform a heat treatment at 150 ⁺ ₋₁₀ °C for 60±5 min. and then				
		Dielectric Strength	In accordance with item No.4			let sit for 24±2 hrs. at room condition.*						

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

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GR4 Series Specifications and Test Methods

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No.	Ite	em	Specifications	Test Method		
		Appearance	No marking defects			
		Capacitance Change	Within ±20%	Apply 110% of the rated voltage for 1,000 ^{±48} hrs. at maximum operating temperature ±3°C. Remove and let sit for 24±2 hrs. at room condition,* then measure.		
17	Life	D.F.	0.05 max.	The charge/discharge current is less than 50mA.		
		I.R.	More than 2,000MΩ	Pretreatment Apply test voltage for 60±5 min. at test temperature.		
		Dielectric Strength	In accordance with item No.4	Remove and let sit for 24±2 hrs. at room condition.*		

^{* &}quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 45 to 75%, Atmospheric pressure: 86 to 106kPa

